Design, Simulation, and Characterisation of Fast Timing Silicon Sensors for HEP applications

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Requirements of Fast Timing

Anticipated ~200 pile-up events per bunch crossing at the HL-LHC, making vertex reconstruction complex

HL-LHC, and FCC-ee aim to achieve 4D particle reconstruction. Active R&D effort to developing sensors which can achieve



[1] Simulated collision at CMS in the HL-LHC

The ATLAS High Granularity Timing Detector (HGTD) aims to provide 4D reconstruction, to do this requires less than 30 ps timing resolution

Must withstand fluences up to 2.5×10^{15} n_eq/cm² over its operational lifetime.



[2] Diagram of the HGTD





CMOS Sensors

- Complimentary Metal-Oxide-Semiconductor (CMOS) is a silicon-based technology integrating sensing and readout onto one chip.
- Ionising particles generate electron hole pairs, in which the electrons drift or diffuse to the NWELL DIODE for collection.
- Has been used in the ITS upgrade at ALICE
- Cost effective, ease of manufacture, low material budget







Low Gain Avalanche Detectors (LGADs)

- Modified n-on-p silicon sensor with internal gain, surrounded by a Junction Terminal Extention (JTE)
- High localised electric field generated within the gain layer, resulting in electron avalanche and ultimately an amplified signal
- Gain layer enables charge multiplication ~×10
- Time resolution: ~30–50 ps
- Hybrid technology: sensor + external ASIC
- Trade-offs: better timing vs. more material & scattering







MiniCACTUS





Cactus-GL

- Successor to miniCACTUS chip
- Monolithic Deep Junction LGAD (DJ-LGAD) fabricated in LFoundry 150nm process with custom gain layer implant. 150 microns thick
- same process used in Liverpool HV-CMOS group
- V0 chip, with aims to achieve 30ps timing







Cactus-GL

- 6 different structures, each with two test diodes
- Been manufactures on two different high resistivity wafers, with different gain layer concentrations
- An epitaxial wafer has also been manufactured as a trial.



Structur **Features** е Reference Structure, no gain layer Α Basic sensor with gain layer В С Interpixel isolation handled by polysilicon ring rather than p-stop D Higher concentration n-well Ε Identical to structure B, with a different guard ring structure F AC LGAD – not currently being investigated

Image of the Cactus-GL Chip





Technology Computer Aided Design (TCAD)

- Create a virtual sensor enabling for design optimisation and testing
- Initially replicated the IRFU design for validation observed consistent results
- Amplitude Gain factor of 4 is observed









I-V Measurements

- Probe station within the clean room used to test the chips
- Needles placed on the pads, measuring both the left and right diodes, and grounding the dummy diodes.
- Multiple chips tested from each of the three manufactured wafers









Lab Characterisation



- Backside and topside biasing show similar breakdown
 behaviour
- Structure D breaks down at ~50 V, consistent across chip
- Structure A (reference) excluded exhibited non-diode behaviour

HR wafer with high gain layer concentration



- Earliest breakdown seen in Structure D (~50 V)
- Higher gain implant increases field resulting in earlier breakdown





Future Work

TCAD Simulations

- Refine simulations to match measured data
- Sentaurus Calibration
 Workbench ML-based
 surrogate models
- Enables efficient search of large design parameter spaces
- Will use to design future iterations of the Cactus-GL



Chip Characterisation

- Neutron irradiation of Cactus-GL samples (NIEL)
- Measure breakdown voltage, leakage current, gain degradation
- Simulate damage effects in TCAD prior to irradiation
- Partake in a test beam for the MiniCACTUS chip





Conclusion

- Joined the CACTUS project
- Replicated simulations of the Cactus-GL chip
- Began lab characterisation of the performance of the Cactus-GL
- Refining simulations to match real data
- Began exploring Machine Learning methods to reduce computational expense of TCAD simulations







Backup: PCB Design







Backup: LGAD E-field







Backup: Types of LGAD







Backup: Types of LGAD







Backup: State of the Art Hybrid Detectors

Name	Sensor	Node [nm]	Pixel Ter size [µm ²]	nporal precision [ps]	Power [W/cm ²]
ETROC	LGAD	65	1300×1300	~ 40	0.3
ALTIROC	LGAD	130	1300×1300	~ 40	0.4
TDCpix	PIN	130	300×300	~ 120	0.32 matrix
TIMEPIX4	PIN, 3D	65	55×55	~ 200	0.3 dig- ital
TimeSpot1	3D	28	55×55	~ 30	3–5





Backup: State of the Art Monolithic Detectors

Name	Sensor N	ode [nm]	$f Pixel size \ [\mu m^2]$	Temporal precision [ps]	${ m Power}$ $[{ m W/cm^2}]$
FASTPIX	MAPS	180	20×20	~130	5-10
miniCACTUS	MAPS	150	500×100	0 ~90	0.15 - 0.3
MonPicoAD	MAPS (SiGe)	130	100×100	~ 36	1.8
Monolith	MAPS (SiGe)	130	100×100	~ 25	0.9





Backup: Epitaxial Wafer







References

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- 3. Reidt, F. (2022). *Upgrade of the ALICE ITS detector*. Nuclear Instruments and Methods in Physics Research Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 1032, 166632. <u>https://doi.org/10.1016/j.nima.2022.166632</u>
- Y. Degerli, F. Guilloux, T. Hemperek, J.-P. Meyer, P. Schwemling. MiniCACTUS: Sub-100 ps timing with depleted MAPS; Nuclear Instruments and Methods in Physics Research Section A: Accelerators, Spectrometers, Detectors and Associated Equipment 2022, 1039, 167022. Available online: <u>https://www.sciencedirect.com/science/article/pii/S0168900222004478</u> (accessed on 17 June 2025).



